

L Number	Hits	Search Text	DB	Time stamp
-	276	(non\$1volatile or flash) with (self or built or bist) and decod\$3 and mode and address near2 buffer	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/08 14:46
-	7	(non\$1volatile or flash) with (self or built or bist) same decod\$3 same mode same address near2 buffer	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/08 12:36
-	19	(non\$1volatile or flash or memory) with (self or built or bist) with test\$3 same decod\$3 same mode same address near2 buffer	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/08 12:38
-	17	((non\$1volatile or flash or memory) with (self or built or bist) with test\$3 same decod\$3 same mode same address near2 buffer) and (array or matrix) same (non\$1volatile or flash or memory) with (self or built or bist) with test\$3 same decod\$3 same mode same address near2 buffer	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/08 12:49
-	8	((((non\$1volatile or flash or memory) with (self or built or bist) with test\$3 same decod\$3 same mode same address near2 buffer) and (array or matrix) same (non\$1volatile or flash or memory) with (self or built or bist) with test\$3 same decod\$3 same mode same address near2 buffer) and (array or matrix) same cell same control same (non\$1volatile or flash or memory) with (self or built or bist) with test\$3 same decod\$3 same mode same address near2 buffer	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/08 12:41
-	4	(((((non\$1volatile or flash or memory) with (self or built or bist) with test\$3 same decod\$3 same mode same address near2 buffer) and (array or matrix) same (non\$1volatile or flash or memory) with (self or built or bist) with test\$3 same decod\$3 same mode same address near2 buffer) and (array or matrix) same cell same control same (non\$1volatile or flash or memory) with (self or built or bist) with test\$3 same decod\$3 same mode same address near2 buffer) not ((non\$1volatile or flash) with (self or built or bist) same decod\$3 same mode same address near2 buffer)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/08 12:48
-	13	(((((non\$1volatile or flash or memory) with (self or built or bist) with test\$3 same decod\$3 same mode same address near2 buffer) and (array or matrix) same (non\$1volatile or flash or memory) with (self or built or bist) with test\$3 same decod\$3 same mode same address near2 buffer) and (instruct\$3 command)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/08 12:50
-	120	Non-volatile with memory with (self adj test or self-test)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/11 10:07
-	6	(Non-volatile with memory with (self adj test or self-test)) and tester same (instruction or command)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/08 14:28
-	3	(Non-volatile with memory with (self adj test or self-test)) and (external near4 tester) same (instruction or command or micro-code or micro near2 code) and (non\$1volatile or flash or EPROM or ROM)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/08 14:31
-	93	((external near4 tester) same (instruction or command or micro-code or micro near2 code) and (non\$1volatile near2 memory or flash or \$2ROM))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/08 14:43

-	0	(( ((external near4 tester) same (instruction or command or micro-code or micro near2 code) and (non\$1volatile near2 memory or flash or \$2ROM))) and (stor\$3 or writ\$3 or receiv\$3) near4 sef\$1test)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/08 14:39
-	0	(( ((external near4 tester) same (instruction or command or micro-code or micro near2 code) and (non\$1volatile near2 memory or flash or \$2ROM))) and (stor\$3 or writ\$3 or receiv\$3) same sef\$1test)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/08 14:39
-	0	(( ((external near4 tester) same (instruction or command or micro-code or micro near2 code) and (non\$1volatile near2 memory or flash or \$2ROM))) and sef\$1test)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/08 14:39
-	9	(( ((external near4 tester) same (instruction or command or micro-code or micro near2 code) and (non\$1volatile near2 memory or flash or \$2ROM))) and (stor\$3 or writ\$3 or receiv\$3) near4 self\$1test)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/08 14:39
-	129	(( ((external near4 tester) same (instruction or command or micro\$1code or configur\$5) and (non\$1volatile near2 memory or flash or \$2ROM))) not ((non\$1volatile or flash) with (self or built or bist) and decod\$3 and mode and address near2 buffer)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/08 14:47
-	372	((external near4 tester or ATE) same (instruction or command or micro\$1code or configur\$5) and (non\$1volatile near2 memory or flash or \$2ROM))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/08 16:34
-	3	(( ((external near4 tester or ATE) same (instruction or command or micro\$1code or configur\$5) and (non\$1volatile near2 memory or flash or \$2ROM))) and (compar\$4 same control same decod\$3 same (BIST or built or self))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/08 14:53
-	140	((external near4 tester) same (instruction or command or micro\$1code or configur\$5) and (non\$1volatile near2 memory or flash or \$2ROM))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/08 16:34
-	231	((external near4 tester or ATE) same (instruction or command or micro\$1code or configur\$5) and (non\$1volatile near2 memory or flash or \$2ROM) and (BIST or built or self))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/08 16:39
-	104	((external near4 tester or ATE) same (instruction or command or micro\$1code or configur\$5) and (non\$1volatile near2 memory or flash or \$2ROM) and (BIST or built\$1in\$1self\$1test or self\$1test))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/10 12:24
-	4	(non\$1volatile or flash) with (self or built or bist) with test\$3 same decod\$3 same mode same address near2 buffer	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/09 12:35
-	202	((tester or ATE) same (instruction or command or micro\$1code or configur\$5) and (non\$1volatile or flash or EEPROM or NVRAM) and (BIST or built\$1in\$1self\$1test or self\$1test))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/10 13:21
-	8	(( ((tester or ATE) same (instruction or command or micro\$1code or configur\$5) and (non\$1volatile or flash or EEPROM or NVRAM) and (BIST or built\$1in\$1self\$1test or self\$1test))) and (test\$3 same decod\$3 same address near2 buffer)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/10 13:21

-	22	((tester or ATE) same (BIST or built\$1in\$1self\$1test or self\$1test) near6 (instruction or command or micro\$1code or configur\$5) and (non\$1volatile near2 memory or flash or EPROM or EEPROM or NVRAM))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/10 14:02
-	1	((stor\$3 writ\$3) near6 (BIST or built\$1in\$1self\$1test or self\$1test) near6 (instruction or micro\$1code or configur\$5) same (first near4 array) same (second near4 array))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/10 16:41
-	11	((stor\$3 writ\$3) near6 (BIST or built\$1in\$1self\$1test or self\$1test) near6 (instruction or micro\$1code) same (cell or array) same (memory))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/10 18:04
-	2	(( (NON\$1VOLATILE) same (MEMORY DEVICE EEPROM) and (CONTROL near2 CIRCUIT) and COMPARATOR and (DETECT near4 DEFECT\$3 near4 MEMORY near4 CELL) same (COMPARE near4 DATA) with (PREDEFINED near4 DATA) and (SELF\$1TEST near6 INSTRUCTION))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/10 17:08
-	2	(( (NON\$1VOLATILE) same (MEMORY DEVICE EEPROM FLASH) and (CONTROL near2 CIRCUIT) and COMPARATOR and (COMPARE near4 DATA) with (PREDEFINED near4 DATA) and (SELF\$1TEST near6 INSTRUCTION))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/10 17:09
-	3	((((stor\$3 writ\$3) near6 (BIST or built\$1in\$1self\$1test or self\$1test) near6 (instruction or micro\$1code) same (cell or array)) and (non\$1volatile or FLASH or EEPROM)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/10 18:08
-	3	((((stor\$3 writ\$3) near6 (BIST or built\$1in\$1self\$1test or self\$1test) near6 (instruction or micro\$1code) same (cell or array)) and (non\$1volatile or FLASH or EEPROM))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/10 18:09
-	2	((((stor\$3 writ\$3) near4 (BIST or built\$1in\$1self\$1test or self\$1test) near4 (instruction or micro\$1code) same (cell or array)) and (non\$1volatile or FLASH or EEPROM))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/10 18:30
-	47	(FLASH with tester).ab.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/10 18:31
-	36	((non\$1volatile FLASH) with tester).ti.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/10 18:51
-	6	("4495567"   "4969148"   "5016212"   "5212776"   "5245572"   "5297148").PN.	USPAT	2004/06/10 18:32
-	2	5410544.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/11 11:14
-	86	((non\$1volatile FLASH) with tester).ab.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/11 09:27
-	0	20030164510.URPN.	USPAT	2004/06/10 18:55
-	2	"6473346".pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/11 10:05

-	6830	(365/201,189.01,189.07).ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/11 10:06
-	8	((365/201,189.01,189.07).ccls.) and (non-volatile with memory with (self adj test or self-test))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/11 10:07
-	2	5640354.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/11 11:14